

**Notice of References Cited**

Application/Control No.

09/922,411

Applicant(s)/Patent Under  
Reexamination  
KHAZEI, MEHYAR

Examiner

Stacy A Whitmore

Art Unit

2812

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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	W	Childs, "Fast interactive EMC analysis for design engineers". IEEE, 1995, pgs. 1-7
	X	Natesan, "Performance driven placement for cell-based design". IEEE, 1995, pgs. 237-240.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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